# ON-LINE RECOGNITION OF DEVELOPING CONTROL CHART PATTERNS QUARTER WAVE STACK MODEL SIMULATION FOR OPTICAL EDGE FILTER DESIGN USING OCTAVE

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### **DEDICATION**

This thesis is dedicated to my father who taught me that, the best kind of knowledge to have is that which is learned for its own sake. This is also dedicated to my mother, who taught me that even the largest task can be accomplished if it is done one step at a time.

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#### ABSTRACT

Optical filter by virtue of their special functions to block a particular wavelength or range of wavelength and transmit the rest of the spectrum have received research attention for the past few decades. Recently, optical filter based on multilayer coating are more focused due to potential to manipulate filter properties by changing layer thickness in order to apply in various fields. Quarter wave stack (QWS) model is one of the approaches to design optical filter such as edge filter. However, to obtain desire minimum specification need an optimization. Therefore, in this study aims to design optical edge filter based QWS model by optical matrix methods in Octave software and fabricate it based on the result obtained using RF magnetron sputtering. Prior to the design, MoS<sub>2</sub> and Si are being choose for high (H) and low (L) refractive index materials respectively. The optimum twenty-four (24) number of layers are determined by calculating maximum transmittance obtained. The Rayleigh wavelength ( $\lambda_{ex}$ ) of 405 nm ,532 nm and 633 nm are selected and 'glass|12HL|air' configuration is set for the design simulation. Then, the cut-on wavelength ( $\lambda_{cut-on}$ ) and cut-off wavelength ( $\lambda_{cut-off}$ ) of successful designed optical edge filter are measured. The result shows that the cut-on wavelength of 408.11 nm, 536 nm and 640.25 nm with minimum effective transmission (MET) of 32.3%, 31.3% and 32% respectively are obtained. Edge filter for  $\lambda_{cut-on} = 633 \text{ nm } \lambda_{ex}$  is selected and fabricated to obtained layer thickness same as generated from the simulation. Afterwards, the fabricated filter is characterized by UV-Vis spectroscopy and field emission scanning electron microscope (FESEM). The result from UV-Vis spectra showed that  $\lambda_{cut-on}$  of fabricated filter at 700 nm with MET of 36%. Moreover, the Filmetric result give the  $\lambda_{cut-on}$  at 640 nm with 30% MET for  $\lambda_{ex} = 633$  nm which is very close as compare to the simulated result. In conclusion, the result of the present study shows a good correlation between simulation and the Filmetric methods with a bit deviation value of  $\lambda_{cut-on}$  for fabricated filter.

#### ABSTRAK

Turas optik berdasarkan fungsi istimewanya untuk menghalang panjang gelombang tertentu atau julat panjang gelombang dan memancarkan spektrum selebihnya telah mendapat perhatian penyelidikan sejak beberapa dekad yang lalu. Kebelakangan ini, turas optik berdasarkan salut berbilang lapis lebih difokuskan disebabkan keupayaan untuk memanipulasi sifat turas dengan mengubah ketebalan lapisan untuk digunakan dalam pelbagai bidang. Model susunan gelombang sukuan (QWS) adalah salah satu pendekatan untuk merekabentuk turas optik seperti turas bucu. Walau bagaimanapun, untuk mendapatkan spesifikasi minimum yang dikehendaki memerlukan pengoptimuman. Oleh itu, kajian ini bertujuan untuk merekabentuk turas optik berasaskan model QWS melalui kaedah matrik optik dalam perisian Octave dan membuatnya berdasarkan hasil yang diperoleh menggunakan percikan RF magnetron. Sebelum rekabentuk, MoS2 dan Si dipilih masing-masing untuk bahan indeks biasan tinggi (H) dan rendah (L). Dua puluh empat (24) lapisan optimum ditentukan dengan mengira tranmitans maksimum yang diperolehi. Panjang gelombang Rayleigh ( $\lambda_{ex}$ ) iaitu 405 nm, 532 nm dan 633 nm dipilih dan konfigurasi 'kaca|12HL|udara' disetkan untuk simulasi rekabentuk. Kemudian, panjang gelombang *cut-on* ( $\lambda_{cut-on}$ ) dan panjang gelombang *cut-off* ( $\lambda_{cut-off}$ ) bagi turas optik bucu yang berjaya direkabentuk diukur. Hasil menunjukkan bahawa  $\lambda_{cut-on}$ 408.11 nm, 536 nm dan 640.25 nm dengan transmitans efectif minimum (MET) adalah masing-masing 32.3%, 31.3% dan 32% diperoleh. Turas bucu untuk  $\lambda_{cut-on} = 633$  nm dipilih dan dibuat untuk mendapatkan ketebalan lapisan yang sama seperti yang dijana daripada simulasi. Selepas itu, turas yang dibuat dicirikan oleh spektroskopi UV-Vis dan mikroskop medan pancaran imbasan elektron (FESEM). Hasil daripada spektra UV-Vis menunjukkan bahawa  $\lambda_{cut-on}$  bagi turas yang dibuat pada 700 nm dengan 36% MET. Tambahan pula, hasil Filmetric memberikan  $\lambda_{cut-on}$  pada 640 nm dengan 30% MET untuk  $\lambda_{ex}$  = 633 nm yang mana sangat hampir berbanding dengan hasil simulasi. Kesimpulannya, hasil kajian ini menunjukkan hubungkait yang baik antara kaedah simulasi dan Filmetric dengan sedikit sisihan bagi nilai  $\lambda_{cut-on}$  untuk turas yang dibuat

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## LIST OF ABBREVIATIONS

MTF	-	Multilayer thin film
Н	-	High reflective index
L	-	Low refractive index
Ν	-	Refractive index
Т	-	Thickness
CSD	-	Chemical Solution Deposition
RF	-	Radio Frequency
UV-VIS	-	Ultraviolet visible
NIR	-	Near infrared
FESEM	-	Field emission Scanning electron microscope
LWP	-	Long wave filter
SWP	-	Short wave filter
nm	-	Nano- meter
М	-	Matrix
PVD	-	Physical vapour deposition
CVD	-	Chemical vapour deposition
CWL	-	Central wavelength
FWHM	-	Full- wave half maximum
ТМ	-	Transverse Magnetic field
TE	-	Transverse Electric field
Р	-	Plane polarisation in which electric vector is parallel
S	-	Plane polarisation in which the electric vector is perpendicular
MET	-	Minimum effective transmission
QWS	-	Quarter Wave Stack
Т	-	Transmission

# LIST OF SYMBOLS

Δ	-	Phase thickness
D	-	Thickness
k	-	Extinction coefficient
$\lambda_o$	-	Reference or central wavelength
$\lambda_L$	-	Wavelength
θ	-	Angle of incidence
В	-	Normalized magnetic field
С	-	Normalized Electric Field
$\eta_o$	-	Admittance
$\phi$	-	Angle of propagation or phase shift
ρ	-	Amplitude of the reflectance coefficient
Υ	-	Admittance of Multilayer C/B
Ν	-	Real part of refractive index
$\lambda_{cut-off}$	-	Cut-off wavelength
$\lambda_{cut-on}$	-	Cut- on wavelength
$\lambda_{ex}$	-	Rayleigh wavelength
λ	-	Wavelength
%		Percentage

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#### **CHAPTER 1**

#### **INTRODUCTION**

#### 1.1 Problem Background

In the present era, optical filters have gained a renews interest due to their increasing request for various applications such as analytical instrument, florescence, microscope, Raman spectrometer, clinical chemistry, or machine vision inspection. These devices are accessible in the market such as band pass filter, high pass filter, low pass filter, and band stop filter (Butt et al. 2016; Elyutin, Butt, and Khonina 2017; Piegari and Flory 2013).

An optical filter can be designed in two different ways, first by using the properties of the deposited materials to absorb light of a given wavelength this is termed as absorption filter (Ng et al. 2019), but this types of filter can be easily damage. The second method of design is using the interference effect of light. This method of design filter is an ideal kind of thin film filter that provides the designer with a wide range of design parameter to produce the require characteristic (Nazar, Ali, and Jasem 2016). The basic types of interference filter consist of a stack of high and low refractive index materials each of one quarter (1/4) wavelength thickness. However, the performance of this types of an optical filter depends on the number of layers, their thickness, and refractive index difference between the layers (Butt et al. 2016; Nazar and Algaffar 2018).

Multilayer thin film (MTF) filter combines attractive properties of several materials. Moreover, MTF filters play a significant role to provide the highest standard such as improvements in transmission, reflection, blocking, and both transmitted and reflected wave front properties. It is comprised of a sequence of boundaries sandwiched between different materials to form a thin film (M. A. Butt, Fomchenkov,

and Khonina 2017). Hence, MTF can be used for many applications such as computer disk, optical filter, anti-reflector, solar cells, and in telecommunication industries (Muhammad A. Butt, Fomchenkov, and Khonina 2017).

MTF filter based on Quarter-wave stack (QWS) model is one the most important method in assemble optical filter that consists of multiple alternative layers of high and lower dielectric materials. QWS model is a basic building block for thinfilm filters which made up of alternating of high and low index materials. Each one quarter (1/4) of an optical wavelength in thickness, the light of a specific wavelength is very strongly reflected. The other benefit of using quarter wave stack is that it is materials independent and straight forward than other method (Nazar et al. 2016).

Normally, MTF filter based QWS model has been fabricated for many years using different methods such as spray pyrolysis (Maho et al. 2016), radio frequency (RF) magnetron sputtering (Randhawa 1988), thermal evaporation (Maho et al. 2016), and sol-gel (Bronnbauer et al. 2018). Design this optical filter using simulation will give the exact thickness, the number of layers, cut-on and cut-off wavelength and minimum transmission.

In this present work, Octave software is used to simulate a computer program for MTF filter design and fabricate it using RF magnetron sputtering as adopted by (Boyd et al. 2015). The aforementioned software has advantage over other due easy to usage, built-in support of a complex number, and extensibility in form of a userdefined function (Selhofer and Oliver 2019). Furthermore, the simulated program designed using octave software to obtained the optical performance of the filter may be used to solve the MTF filter fabrication problems and also hoping that high performance filter may be obtained.

Molybdenum disulphide (MoS<sub>2</sub>) and Silicon (Si) materials are used in optical edge filter for both simulation and fabrication study as adopted (Chromik et al. 2017; Cong et al. 2018). This structural and the optical properties of the fabricated filter can be characterized using field emission scanning electron microscope (FESEM) and ultraviolet visible (UV-Vis) spectroscopy. The result obtained should be similar.

### **1.2 Problem Statement**

In recent years, the MTF edge filter has gained a lot of research interest due to their growing demand in numerous applications. The edge filters have an ultra-steep edge between the absorbing and transmitting spectral region. It has advantage over other types of filter due an excellent blocking of laser line, environmental stable with near infinite life time.

The optical filter can be designed using optical software such as optilayer software (Xie et al. 2017), open filter software (Elyutin et al. 2017), MATLAB (Abbas, Salman, and Hashim 2017) and fabricated using one of the fabricating method such as RF magnetron sputtering (Benetti et al. 2017), chemical solution deposition (Pejjai et al. 2017), electrodeposition (Maho et al. 2016), solution growth (Eslamian 2017), thermal evaporation and spray pyrolysis method. However, Trubetskov (2013), Kedawat (2014) and Zhupanov (2017) affirmed that the design of optical filter followed by the fabrication of the attained result gives better optical performance and optimum number of layers

In this regard, this study aim is to use optical matrix methods in octave software to design MTF Edge filter based on QWS model and fabricate it via RF magnetron sputtering technique and compare the result with Filmetric web application.

#### **1.3** Objectives of the Research

The objectives of this research are as follows:

- (a) To design and optimize a QWS model simulation for MTF optical filter
- (b) To fabricate optical edge filter using QWS model simulation result.
- (c) To characterize the structural and optical properties of the fabricated edge filter and measure it optical performance.

#### **1.4** Scope of the Research

The MTF edge filter based on QWS model is simulated using octave software. Optimization on the number of layers, the cut-on and cut-off wavelength of the edge filter performance. The simulation result obtained is fabricated using MoS<sub>2</sub>/Si series via RF magnetron sputtering. The characterization is identified using UV-Vis spectrometer and FESEM for optical and structural properties respectively. The minimum effective transmission, cut-on and cut-off wavelength of fabricated filter is determined from UV- Vis spectrum analysis. The performance of edge filter is compared with the result obtained from filmetric web application

#### **1.5** Significant of the Research

The finding of this research contributes greatly to the benefit of optical industries to designing MTF edge filters. It also reduces the costs of production and time for fabrication. Since the simulation result give the exact thickness and the cuton and cut-off wavelength by using the same approach with the same materials, one can easily fabricate multilayer thin film edge filter based on QWS model approach. It is possible to fabricate an optical filter with a minimum number of layers rather than using a larger number of layers with the same output. In this study working under trial and error can be discontinued.

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